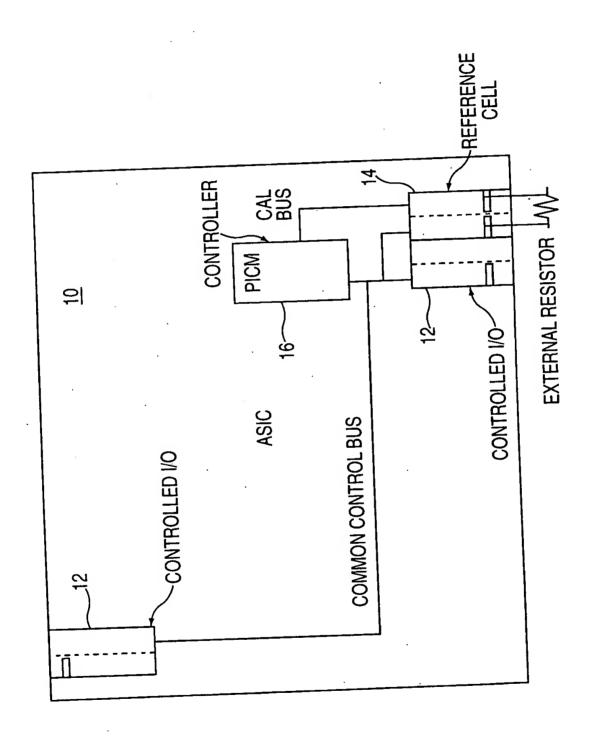
1/10 TERRY C. COUGHLIN, JR., ET A END920010050US1



ASIC ARCHITECTURE FIG. 1

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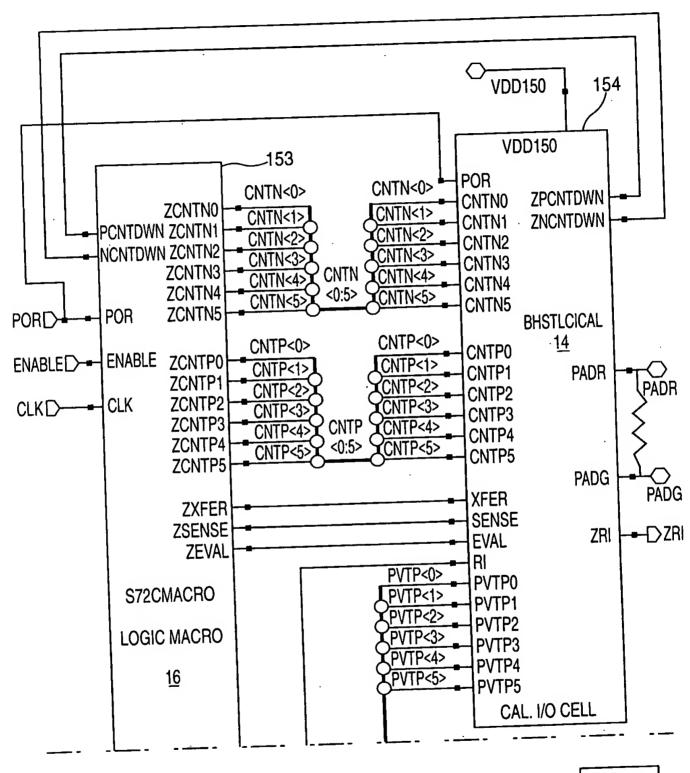
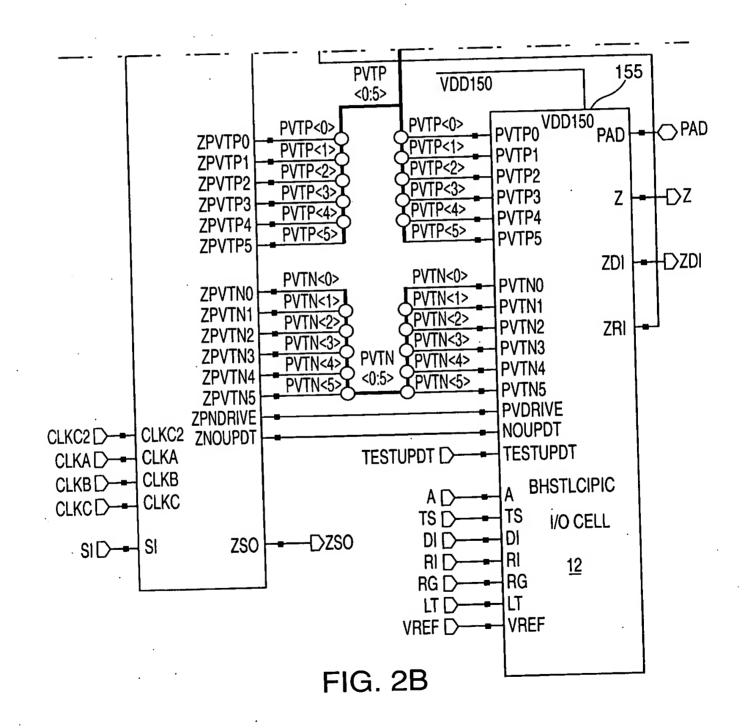


FIG. 2A

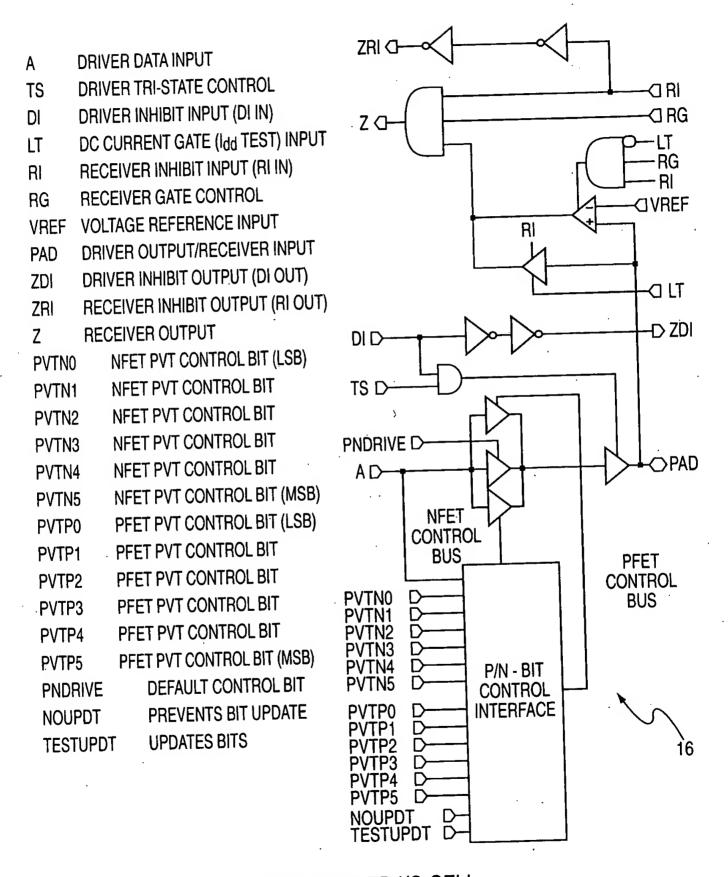
2-A 2-B

FIG. 2

3/10 END920010050US1



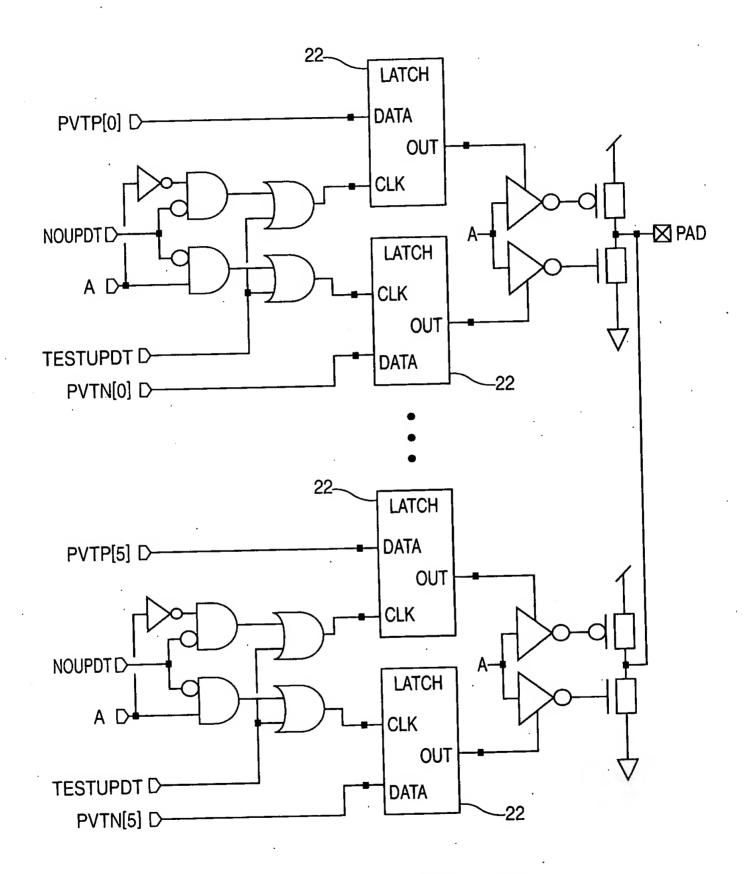
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CONTROLLED I/O CELL

FIG. 3

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DRIVER-IMPEDANCE UPDATE LOGIC FIG. 4

=INPUTS=			OUTPUTS					
	NOUPDT	TESTUPDT	P-BITS	N-BITS	COMMENTS			
V	1	0	NC ¹	NC ¹	INPUT BITS CHANGING			
-		0	UPDATE ²	HOLD ²	UPDATE P-BITS ONLY			
0	1 0	0	HOLD ³	UPDATE ³	UPDATE N-BITS ONLY			
1			 		FORCE UPDATE TO ALL P/N-BITS			
X	X	1	UPDATE4		ED AND THE I/O WILL HOLD THE			

- 1. WHEN "NOUPDT" IS HIGH, THE INPUT CONTROL BITS WILL BE UPDATED AND THE I/O WILL HOLD THE PRESENT STATE OF THE CONTROL BITS UNTIL "NOUPDT" GOES LOW. THIS PREVENTS THE I/O FROM CHANGING THE OUTPUT IMPEDANCE WHILE THE INPUT CONTROL BITS ARE UNSTABLE.
- 2. WHEN THE DATA INPUT "A" CHANGES FROM A HIGH TO A LOW STATE, THE PULL-UP IMPEDANCE WILL BE UPDATED. THE P-BITS WILL BE LATCHED WHEN "A" TOGGLES FROM LOW TO HIGH.
- 3. WHEN THE DATA INPUT "A" CHANGES FROM A LOW TO A HIGH STATE, THE PULL-DOWN IMPEDANCE WILL BE UPDATED. THE N-BITS WILL BE LATCHED WHEN "A" TOGGLES FROM HIGH TO LOW.
- 4. WHEN "TESTUPDT" IS HIGH, ALL THE DATA LATCHES WILL BECOME TRANSPARENT AND BOTH THE PULL-UP AND PULL-DOWN IMPEDANCE WILL BE UPDATED.

NOTE: "TESTUPDT" IS USEFUL TO THE USER TO UPDATE THE OUTPUT IMPEDANCE IF THE I/O HAS BEEN SITTING IN Hi-Z OR THE "A" INPUT HAS NOT TOGGLED FOR A LONG PERIOD OF TIME.

DRIVER IMPEDANCE UPDATE TABLE FIG. 5

EINPUTS ===		OUTPUTS				
A =	TS	DI E	PNDRIVE	PVTN[0:5] PVTP[0:5]	PAD	ZDI
•	0	-	-	-	Hi-Z ¹	DI
	-	0	-	-	Hi-Z ¹	D1
_	1	1	0	0	Hi-Z ²	D1
	1	1	-	13	· A	D1
_	1	1	1	-	Α	D1

- 1. PAD IS Hi-Z IF DRIVER IS NOT EXTERNALLY TERMINATED. PAD IS AT "V_{ddd}/2" IF DRIVER IS TERMINATED (OFF-CHIP).
 2. PNDRIVE=0 IS FOR TEST ONLY. THIS FORCES THE DEFAULT BIT OFF SUCH THAT THE LSB'S CAN BE TESTED.
 3. AT LEAST ONE PVTN BIT AND ONE PVTP BIT MUST BE AT A LOGIC "1".

NOTES: A. LOGICAL "1" = $V_{ddq} = V_{DD150} = 1.5V$. (NOMINAL) B. NEW DELAY RULE (NDR) WILL BE BASED ON DRIVER TERMINATED OFF-CHIP.

DRIVER TRUTH TABLE FIG. 6

=INPUTS						OUTPUTS			
PAD ==	LT	RI	RG	VREF	Z	= ZRI	COMMENTS		
_	-	-	0	-	0	RI	TEST MODE		
_		0	-	-	0	RI	TEST MODE		
11	0	1	1		1	·RI	FUNCTIONAL MODE		
02	0	1	1	-	0	. RI	FUNCTIONAL MODE		
13	1	1	1	-	1	RI	BYPASS MODE		
04	 	1	1	-	0	RI	BYPASS MODE		
TO THE HEAVE AND Vada < Vad.									

- 1. PAD INPUT REQUIRES HSTL LEVEL "HIGH" AND Vddq < Vdd.
- 2. PAD INPUT REQUIRES HSTL LEVEL "LOW."
- 3. PAD INPUT REQUIRES CMOS LEVEL "HIGH" AND Vddq = Vdd.
- 4. PAD INPUT REQUIRES CMOS LEVEL "LOW."

RECEIVER TRUTH TABLE

FIG. 7

D ZRI

>-D ZNCNTDWN

ZPCNTDWN

PADR

D PADG

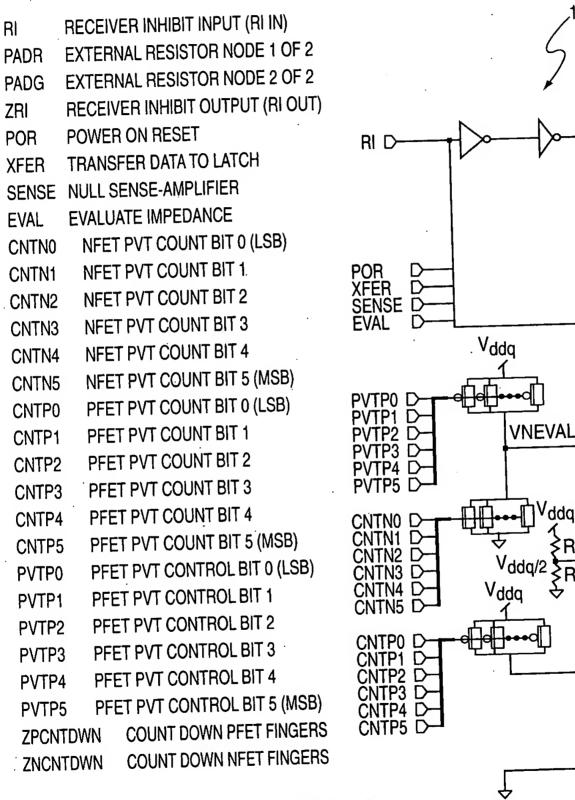


FIG. 8

	, .							
INPUTS							OUTPUTS	
= RI	= POR =	EVAL	SENSE	XFER		ZPCNT DWN	ZNCNT DWN	
0	X	X	X	X	Х	0	0	
X	0	X	Х	X	X	0	0	
1	1	1	1	1	X	X ¹	X ¹	
1	1	1	0	1	Х	12	13	
1	1	1	0	1	· X	04	05	
1	1	. 1	. 0	0	Χ	LATCH ⁶	LATCH ⁶	
1	1	0	0	0	Х	HOLD ⁷	HOLD ⁷	
L AND COMPARATOR INDITE								

- 1. EVAL = 1, POWER UP THE CELL; SENSE = 1, NULLS COMPARATOR INPUTS.
- 2. ZPCNTDWN = 1, WHEN VPADR $> V_{ddq}/2$
- 3. ZNCNTDWN = 1, WHEN VNEVAL < Vddq/2
- 4. ZPCNTDWN = 0, WHEN VPADR < Vddq/2
- 5. ZNCNTDWN = 0, WHEN VNEVAL $> V_{ddq}/2$
- 6. XFER = 0, LATCHES THE COMPARATOR OUTPUTS.
- 7. THE REFERENCE I/O IS POWERED DOWN AND THE PRESENT STATES OF THE OUTPUTS ARE HELD.

REF TRUTH TABLE FIG. 9

